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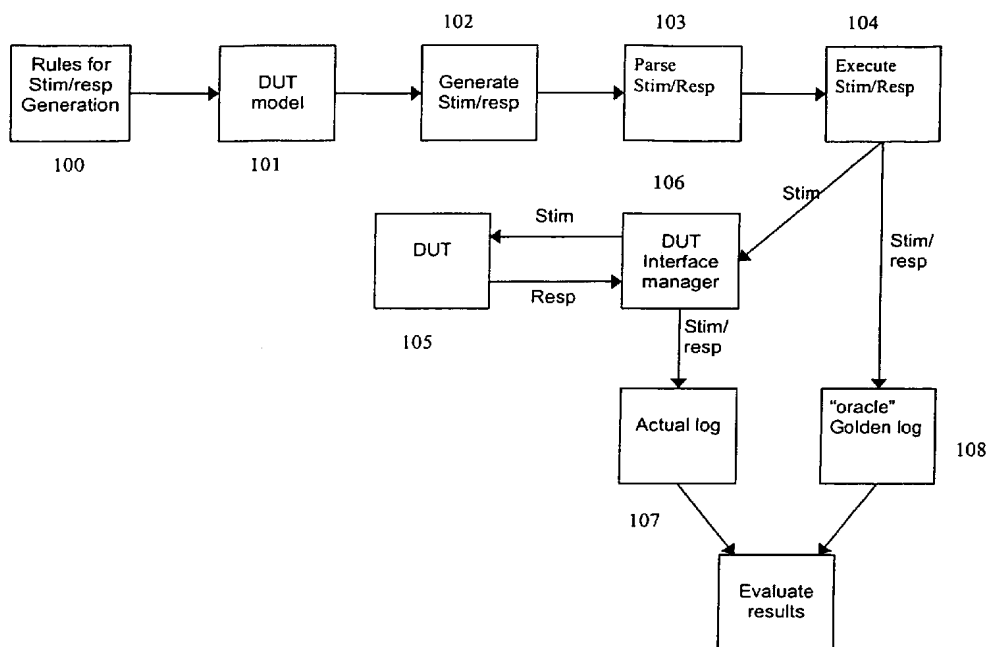
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(54) Title: TESTING OF EMBEDDED SYSTEMS



(57) Abstract: An embedded device testing system for comparing actual device under test input/output vector pairs with modelled device under test input/output vector pairs, wherein actual device under test output vectors are sampled in accordance with a predefined timing reference.



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